Agilent Electronic Test Products to be Used by NXP in WiGig RFIC Demo at CES

Agilent Technologies Inc. announced that its electronic test equipment will be used by NXP Semiconductors N.V. in a demonstration of its beam-forming technology for the next generation of communication and radar products at the International Consumer Electronics Show in Las Vegas, Jan. 10-13. NXP will demonstrate a multi-Gbps wireless link based onthe Wireless Gigabit Alliance and the IEEE 802.11ad specifications.

The NXP demonstration will include equipment from Agilent, the only commercial provider of signal-creation and modulation-analysis software and hardware for the WiGig and IEEE 802.11ad physical-layer specifications. The test equipment will provide signal creation and analysis capabilities to complement NXP’s RFIC chipset, on display in Las Vegas.

NXP’s receiver front-end is a phased-array system with eight antennas and eight RX paths. The antenna array is implemented on a low-cost laminate, and active circuitry is realized in CMOS 45-nm technology. Electronic beam-forming increases the link distance by about three times compared to a single antenna system, while at the same time providing broad angular scanning.

NXP’s technology enables highly integrated, low-power, beam-forming and beam-steering systems for increased WiGiG/802.11ad room coverage. Next-generation car-radar systems will also profit from these core developments, enabling integration of CMOS phased-array millimeter-wave circuits with IF, ADC and DSP blocks into a highly integrated, low-power, car-radar signal processor.

“We are pleased to provide test hardware and software capabilities to support the demonstration of NXP’s core technology,” said Guy Séné, president of Agilent’s Electronic Measurement Group. “We are delighted that our early investments and continued commitment to this technology and the WiGig Alliance are allowing the industry to design and develop products more rapidly in the 60-GHz frequency band through our superior capabilities in wide-bandwidth modulation, analysis and millimeter applications.”

Visitors will be able to see the demonstration at NXP Booth CP8, in the Central Plaza of the Las Vegas Convention Center.

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